

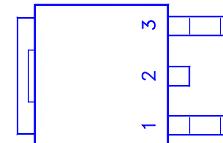
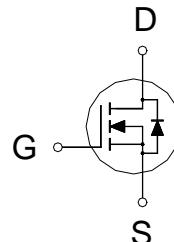
NIKO-SEM
**N-Channel Enhancement Mode
Field Effect Transistor**
PD6A4BA

TO-252

Halogen-Free & Lead-Free

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
40V	12mΩ	35A

**ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	40	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current ²	I_D	35	A
		22	
Pulsed Drain Current ¹	I_{DM}	70	A
Avalanche Current	I_{AS}	20	
Avalanche Energy	E_{AS}	20	mJ
Power Dissipation	P_D	32	W
		13	
Junction & Storage Temperature Range	T_J, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		3.8	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	

¹Pulse width limited by maximum junction temperature.²Package limitation current is 30A**ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	40			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.3	1.78	2.3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 32V, V_{GS} = 0V$			1	μA
		$V_{DS} = 30V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			10	
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 4.5V, I_D = 15A$		12	16	$\text{m}\Omega$
		$V_{GS} = 10V, I_D = 20A$		10	12	

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Forward Transconductance ¹	g_{fs}	$V_{DS} = 5V, I_D = 20A$		75		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 20V, f = 1MHz$		843		pF
Output Capacitance	C_{oss}			106		
Reverse Transfer Capacitance	C_{rss}			62		
Gate Resistance	R_g		$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$	2.4		Ω
Total Gate Charge ²	$Q_{g(VGS=10V)}$	$V_{DS} = 20V, I_D = 20A$		17.2		nC
	$Q_{g(VGS=4.5V)}$			9.5		
Gate-Source Charge ²	Q_{gs}			2.7		
Gate-Drain Charge ²	Q_{gd}			2.7	4.5	6.3
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DS} = 20V$		15		nS
Rise Time ²	t_r			11		
Turn-Off Delay Time ²	$t_{d(off)}$			44		
Fall Time ²	t_f			10		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current ³	I_S				24	A
Forward Voltage ¹	V_{SD}	$I_F = 20A, V_{GS} = 0V$			1.3	V
Reverse Recovery Time	t_{rr}	$I_F = 20A, dI_F/dt = 100A / \mu S$		11.8		nS
Reverse Recovery Charge	Q_{rr}			3.4		nC

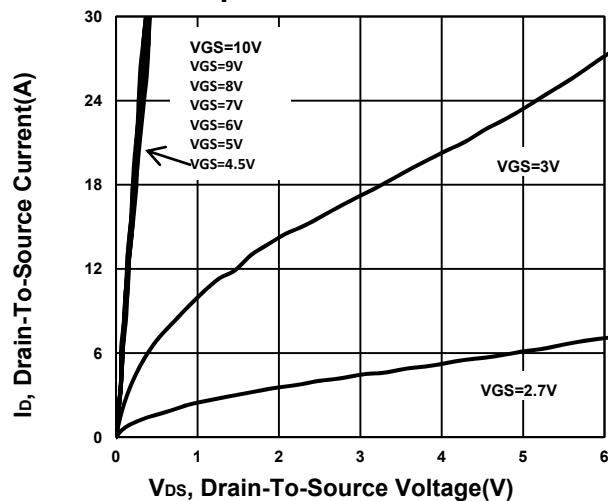
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.³Package limitation current is 30A

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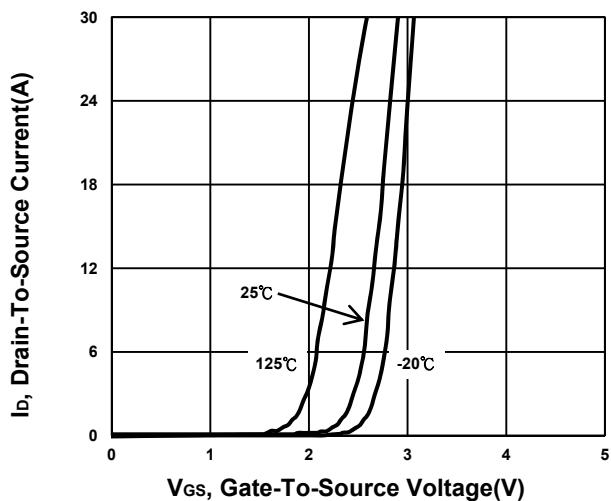
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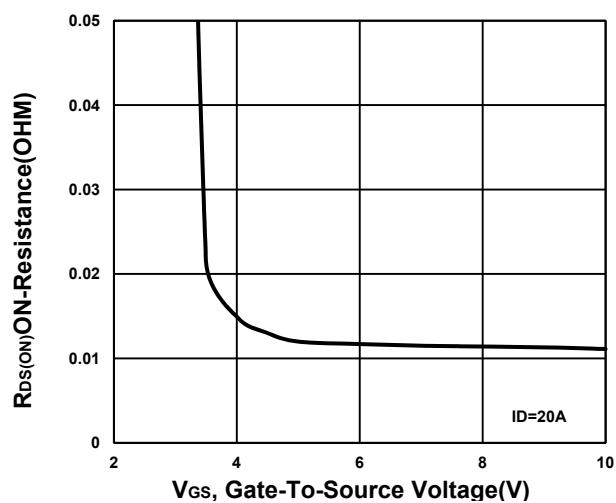
Output Characteristics



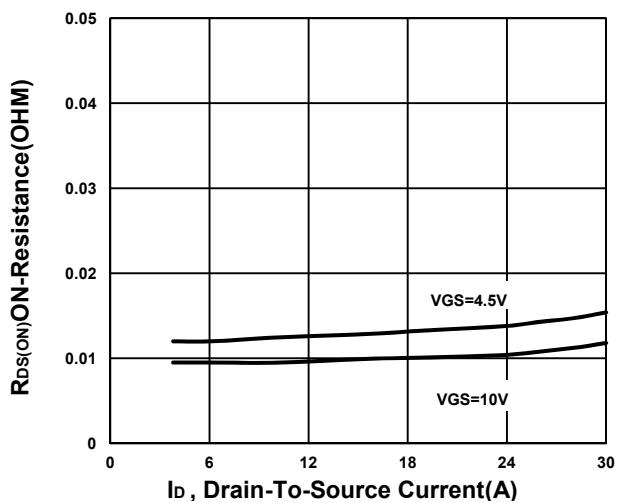
Transfer Characteristics



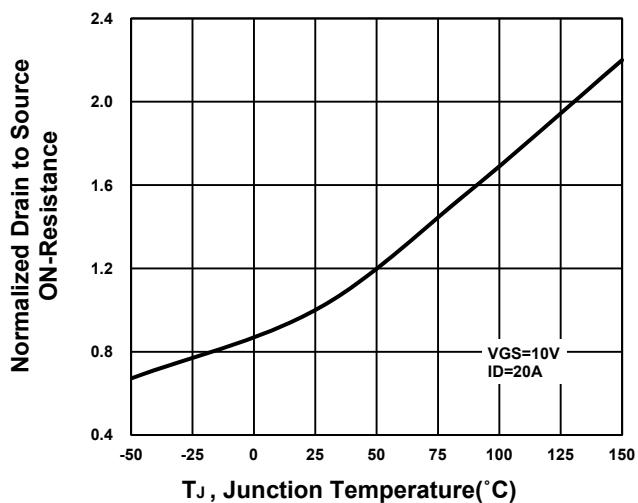
On-Resistance VS Gate-To-Source



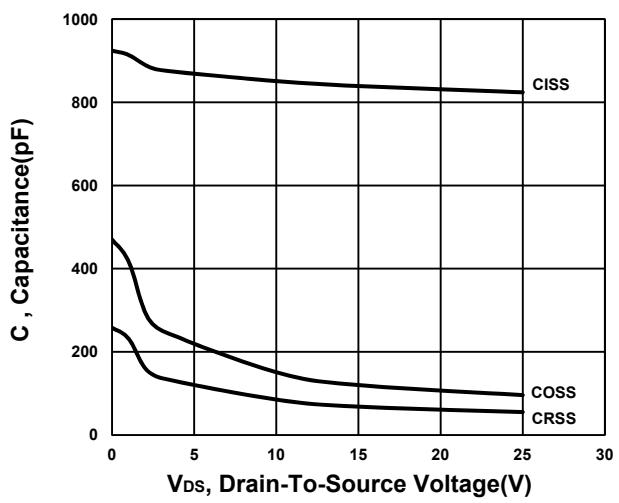
On-Resistance VS Drain Current



On-Resistance VS Temperature



Capacitance Characteristic



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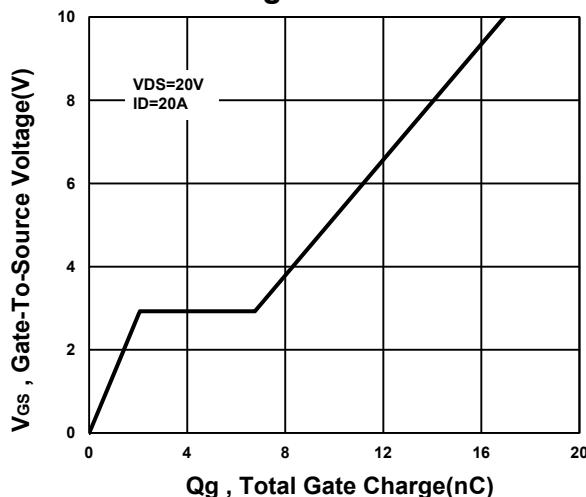
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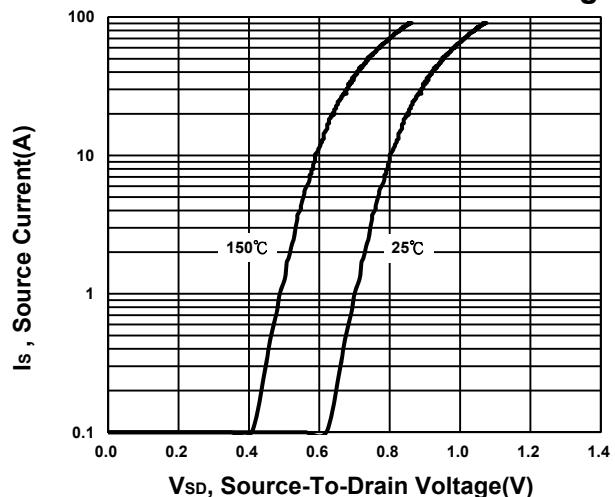
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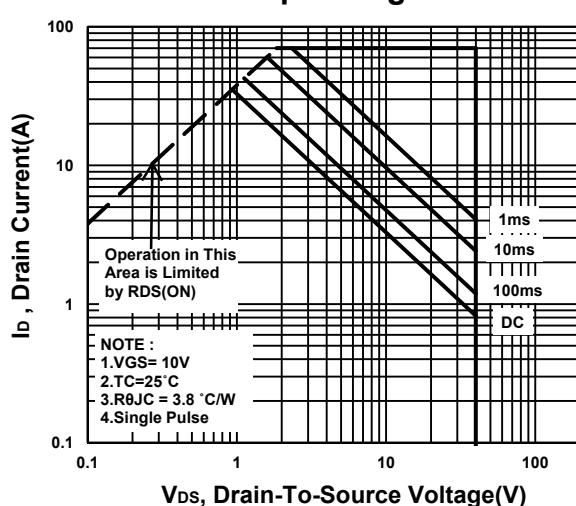
Gate charge Characteristics



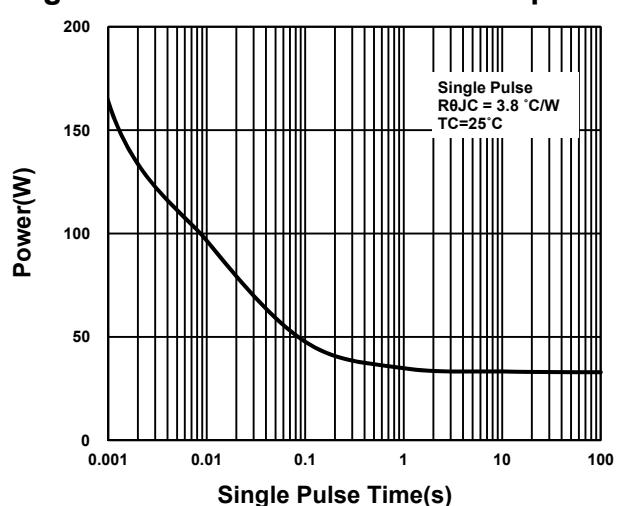
Source-Drain Diode Forward Voltage



Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve

